256×8 bit Electrically Erasable PROM (based on Serial Presence Detect)

BR34L02FV-W

The BR34L02FV-W is a 2k bit EEPROM memory with write-protect function having independent rewrite inhibit area, developed for a DIMM that uses synchronous DRAM memory, and a RIMM that uses RAMBUS DRAM memory. This is a memory IC that reads ID in order for the Plug & Play feature to operate.

* *2C BUS is a registered trademark of Philips.

**Applications**

General purpose

**Features**

1) 256k registers × 8 bits serial architecture
2) Single power supply (1.7V to 5.5V)
3) Two wire serial interface
4) Page Write Function (16byte)
5) Write Protect Mode
   - Write protect 1 (Onetime Rom) : 00h to 7Fh
   - Write protect 2 (Hardwire WP PIN) : 00h to FFh
6) Low Power consumption
   - Write (5V) : 1.2mA (Typ.)
   - Read (5V) : 0.2mA (Typ.)
   - Standby (5V) : 0.1µA (Typ.)
7) DATA security
   - Write protect feature (WP pin)
     Inhibit to WRITE at low Vcc
8) Small package - - - - - - SSOP-B8 pin
9) High reliability fine pattern CMOS technology
10) Endurance : 1,000,000 erase/write cycles
11) Data retention : 40years
12) Filtered inputs in SCL•SDA for noise suppression
13) Initial data FFh in all address

**Absolute maximum ratings** (Ta=25°C)

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Limits</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Supply voltage</td>
<td>Vcc</td>
<td>−0.3 to +6.5</td>
<td>V</td>
</tr>
<tr>
<td>Power dissipation</td>
<td>Pd</td>
<td>300(SSOP-B8) *1</td>
<td>mW</td>
</tr>
<tr>
<td>Storage temperature</td>
<td>Tstg</td>
<td>−65 to +125</td>
<td>°C</td>
</tr>
<tr>
<td>Operating temperature</td>
<td>Topr</td>
<td>−40 to +85</td>
<td>°C</td>
</tr>
<tr>
<td>Terminal voltage</td>
<td></td>
<td>−0.3 to Vcc+0.3</td>
<td>V</td>
</tr>
</tbody>
</table>

*1 Reduced by 3.0mW for each increase in Ta of 1°C over 25°C.
Memory ICs

● Recommended operating conditions (Ta=25°C)

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Limits</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Supply voltage</td>
<td>VCC</td>
<td>1.7 to 5.5</td>
<td>V</td>
</tr>
<tr>
<td>Input voltage</td>
<td>VIN</td>
<td>0 to VCC</td>
<td>V</td>
</tr>
</tbody>
</table>

● DC operating characteristics (Unless otherwise specified Ta=−40 to 85°C, VCC=1.7 to 5.5V)

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Min.</th>
<th>Typ.</th>
<th>Max.</th>
<th>Unit</th>
<th>Conditions</th>
</tr>
</thead>
<tbody>
<tr>
<td>&quot;HIGH&quot; input voltage 1</td>
<td>VIH1</td>
<td>−</td>
<td>−</td>
<td>−</td>
<td>V</td>
<td>2.5V≤VCC≤5.5V</td>
</tr>
<tr>
<td>&quot;LOW&quot; input voltage 1</td>
<td>VIL1</td>
<td>−</td>
<td>−</td>
<td>−</td>
<td>V</td>
<td>2.5V≤VCC≤5.5V</td>
</tr>
<tr>
<td>&quot;HIGH&quot; input voltage 2</td>
<td>VIH2</td>
<td>−</td>
<td>−</td>
<td>−</td>
<td>V</td>
<td>1.7V≤VCC≤2.5V</td>
</tr>
<tr>
<td>&quot;LOW&quot; input voltage 2</td>
<td>VIL2</td>
<td>−</td>
<td>−</td>
<td>−</td>
<td>V</td>
<td>1.7V≤VCC≤2.5V</td>
</tr>
<tr>
<td>1st input leakage current 1</td>
<td>IL1</td>
<td>−1</td>
<td>−</td>
<td>+1</td>
<td>µA</td>
<td>VIN=0V to VCC</td>
</tr>
<tr>
<td>2nd input leakage current 1</td>
<td>IL1</td>
<td>−1</td>
<td>−</td>
<td>+15</td>
<td>µA</td>
<td>VIN=0V to VCC (WP)</td>
</tr>
<tr>
<td>Output leakage current</td>
<td>IOL</td>
<td>−</td>
<td>−</td>
<td>+1</td>
<td>µA</td>
<td>VOUT=0V to VCC</td>
</tr>
<tr>
<td>Operating current</td>
<td>ICC1</td>
<td>−</td>
<td>−</td>
<td>2.0</td>
<td>mA</td>
<td>VCC=5.5V, fSCL=400kHz, t=5µs, Byte Write, Page Write, Write Protect</td>
</tr>
<tr>
<td>Standby current</td>
<td>ICC2</td>
<td>−</td>
<td>−</td>
<td>0.5</td>
<td>mA</td>
<td>VCC=5.5V, fSCL=400kHz, Random Read, Current Read, Sequential Read</td>
</tr>
</tbody>
</table>

*This product is not designed for protection against radioactive rays.

● Memory cell characteristics (Ta=25°C, VCC=1.7 to 5.5V)

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Min.</th>
<th>Typ.</th>
<th>Max.</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Write/Erase Cycle</td>
<td>+1</td>
<td>1,000,000</td>
<td>−</td>
<td>cycle</td>
</tr>
<tr>
<td>Data Retention</td>
<td>+1</td>
<td>40</td>
<td>−</td>
<td>year</td>
</tr>
</tbody>
</table>

*1 Not 100% Tested

● Dimension

![Physical Dimension SSOP-B8](Units:mm)
Memory ICs

● Block diagram

![Block Diagram]

Fig.2 BLOCK DIAGRAM

● Pin configuration

![Pin Layout]

Fig.3 PIN LAYOUT

● Pin descriptions

<table>
<thead>
<tr>
<th>Pin name</th>
<th>I / O</th>
<th>Function</th>
</tr>
</thead>
<tbody>
<tr>
<td>Vcc</td>
<td>–</td>
<td>Power supply</td>
</tr>
<tr>
<td>GND</td>
<td>–</td>
<td>Ground (0V)</td>
</tr>
<tr>
<td>A0, A1, A2</td>
<td>IN</td>
<td>Slave address set</td>
</tr>
<tr>
<td>SCL</td>
<td>IN</td>
<td>Serial clock input</td>
</tr>
<tr>
<td>SDA</td>
<td>IN / OUT</td>
<td>Slave and word address, serial data input, serial data output</td>
</tr>
<tr>
<td>WP</td>
<td>IN</td>
<td>Write protect input</td>
</tr>
</tbody>
</table>

*1 An open drain output requires a pull up resistor.
*2 WP Pin has a Pull-Down resistor. Please be left unconnected or connect to GND when WP feature is not in use.
Test circuit

OUTPUT=“L”

Fig.4 "L" OUTPUT VOLTAGE TEST CIRCUIT

Fig.5 INPUT/OUTPUT CURRENT TEST CIRCUIT

Fig.6 POWER CONSUMPTION TEST CIRCUIT

Fig.7 STANDBY CURRENT VOLTAGE TEST CIRCUIT
AC operating characteristics (Unless otherwise specified Ta = −40 to 85°C, Vcc=1.7 to 5.5V)

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Fast-mode 2.5V ≤ Vcc ≤ 5.5V</th>
<th>Standard-mode 1.7V ≤ Vcc ≤ 5.5V</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Clock frequency</td>
<td>fSCL</td>
<td>–</td>
<td>–</td>
<td>400</td>
</tr>
<tr>
<td>Data clock &quot;HIGH&quot; period</td>
<td>tHIGH</td>
<td>0.6</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Data clock &quot;LOW&quot; period</td>
<td>tLOW</td>
<td>1.2</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>SDA and SCL rise time</td>
<td>tR</td>
<td>–</td>
<td>–</td>
<td>0.3</td>
</tr>
<tr>
<td>SDA and SCL fall time</td>
<td>tF</td>
<td>–</td>
<td>–</td>
<td>0.3</td>
</tr>
<tr>
<td>Start condition hold time</td>
<td>tHD:STA</td>
<td>0.6</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Start condition setup time</td>
<td>tSU:STA</td>
<td>0.6</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Input data hold time</td>
<td>tHD:DAT</td>
<td>0</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Input data setup time</td>
<td>tSU:DAT</td>
<td>50</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Output data delay time</td>
<td>tPD</td>
<td>0.1</td>
<td>–</td>
<td>0.9</td>
</tr>
<tr>
<td>Output data hold time</td>
<td>tDH</td>
<td>0.1</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Stop condition setup time</td>
<td>tSU:STO</td>
<td>0.6</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Bus free time</td>
<td>tBUF</td>
<td>1.2</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>Write cycle time</td>
<td>tWR</td>
<td>–</td>
<td>5</td>
<td>–</td>
</tr>
<tr>
<td>Noise spike width (SDA and SCL)</td>
<td>tf</td>
<td>–</td>
<td>–</td>
<td>0.1</td>
</tr>
<tr>
<td>WP hold time</td>
<td>tHD:WP</td>
<td>0</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>WP setup time</td>
<td>tSU:WP</td>
<td>0.1</td>
<td>–</td>
<td>–</td>
</tr>
<tr>
<td>WP high period</td>
<td>tHIGH:WP</td>
<td>1.0</td>
<td>–</td>
<td>–</td>
</tr>
</tbody>
</table>

+1 Not 100% tested.
**Synchronous data timing**

- SDA data is latched into the chip at the rising edge of SCL clock.
- Output data toggles at the falling edge of SCL clock.

**Write cycle timing**

- SDA data is latched into the chip at the rising edge of SCL clock.
- Output data toggles at the falling edge of SCL clock.

---

**Fig.8 SYNCHRONOUS DATA TIMING**

**Fig.9 WRITE CYCLE TIMING**
For the WRITE operation, WP must be “LOW” during the period of time from the rising edge of the clock which takes in D0 of first byte until the end of tWR. (See Fig.10(a) ) During this period, WRITE operation is canceled by setting WP “HIGH”. (See Fig.10(b))

In the case of setting WP “HIGH” during tWR, WRITE operation is stopped in the middle and the data of accessing address is not guaranteed. Please write correct data again in the case.
Memory ICs

- **Device operation**

  1) Start condition (Recognition of start bit)
  - All commands are preceded by the start condition, which is a HIGH to LOW transition of SDA when SCL is HIGH.
  - The device continuously monitors the SDA and SCL lines for the start condition and will not respond to any command until this condition has been met.
  (See Fig.8 SYNCHRONOUS DATA TIMING)

  2) Stop condition (Recognition of stop bit)
  - All communications must be terminated by a stop condition, which is a LOW to HIGH transition of SDA when SCL is HIGH.
  (See Fig.8 SYNCHRONOUS DATA TIMING)

  3) Notice about write command
  - In the case that stop condition is not executed in WRITE mode, transferred data will not be written in a memory.

  4) Device addressing
  - Following a START condition, the master output the device address to be accessed.
  - The most significant four bits of the slave address are the “device type identifier”.
  - For the device this is fixed as “1010”.
  (In access to WP resister, this code use “0110”.)
  - The next three bit (device address) address a particular to the bus.
  - The device address is defined by the start of A0, A1 and A2 input pins. This IC works only when the device address inputted from SDA pin correspond to the state of A0, A1 and A2 input pins. Using this address scheme, up to eight device may be connected, to the bus. The last bit of the stream (R/W - - - READ/WRITE) determines the operation to the performed.

    | Device Type | Device Address | R/W | Access to |
    |-------------|---------------|-----|-----------|
    | 1010        | A2 ; A1 ; A0  | 0/1 | Memory    |
    | 0110        | A2 ; A1 ; A0  | 0/1 | WP Resister |

  5) Write protect command
  - Write Protect Command is to cancel any write command, which access to the address 00 to 7Fh.
  - Write Protect Resister can be written for once. (Onetime Rom)
  - Once this command is executed, the data is protected forever.

  6) Write protect pin (WP)
  - When WP pin set to Vcc (H level), write protect is set for 256words (all address).
  - When WP pin set to GND (L level), it is enable to write 256words (all address).
  - If permanent protection is done by Write Protect command, lower half area (00 to 7Fh address) is inhibited writing regardless of WP pin state.
  - WP pin has a Pull-Down resister. Please be left unconnected or connect to GND when WP feature is not in use.
7) Acknowledge

- Acknowledge is a software convention used to indicate successful data transfers. The Transmitter device will release the bus after transmitting eight bits.
  (When inputting the slave address in the write or read operation, transmitter is µ-COM. When outputting the data in the read operation, it is this device.)
- During the ninth clock cycle, the receiver will pull the SDA line LOW to acknowledge that the eight bits of data has been received.
  (When inputting the slave address in the write or read operation, receiver is this device. When outputting the data in the read operation, it is µ-COM.)
- The device will respond with an Acknowledge after recognition of a START condition and its slave address (8bit).
- In the WRITE mode, the device will respond with an Acknowledge, after the receipt of each subsequent 8-bit word (word address and write data).
- In the READ mode, the device will transmit eight bit of data, release the SDA line, and monitor the line for an Acknowledge.
- If an Acknowledge is detected, and no STOP condition is generated by the master, the device will continue to transmit the data.
  If an Acknowledge is not detected, the device will terminate further data transmissions and await a STOP condition before returning to the standby mode.
  (See Fig.11 ACKNOWLEDGE RESPONSE FROM RECEIVER)

![Fig.11 ACKNOWLEDGE RESPONSE FROM RECEIVER](image-url)
• **Byte write**

![Fig.12 BYTE WRITE CYCLE TIMING](image)

- By using this command, the data is programmed into the indicated word address.
- When the master generates a STOP condition, the device begins the internal write cycle to the nonvolatile memory array.

• **Page write**

![Fig.13 PAGE WRITE CYCLE TIMING](image)

- This device is capable of sixteen byte Page Write operation.
- When two or more byte data are inputted, the four low order address bits are internally incremented by one after the receipt of each word. The four higher order bits of the address (WA7 to WA4) remain constant.
- If the master transmits more than sixteen words, prior to generating the STOP condition, the address counter will "roll over", and the previous transmitted data will be overwritten.
• Current read

Fig.14 CURRENT READ CYCLE TIMING

- In case that the previous operation is Random or Current Read (which includes Sequential Read respectively), the internal address counter is increased by one from the last accessed address (n).
- Thus Current Read outputs the data of the next word address (n+1).
- If the last command is Byte or Page Write, the internal address counter stays at the last address (n).
- Thus Current Read outputs the data of the word address (n).
- If an Acknowledge is detected, and no STOP condition is generated by the master (µ-COM), the device will continue to transmit the data. [It can transmit all data (2kbit 256word)]
- If an Acknowledge is not detected, the device will terminate further data transmissions and await a STOP condition before returning to the standby mode.

NOTE) If an Acknowledge is detected with “Low” level, not “High” level, command will become Sequential Read. So the device transmits the next data, Read is not terminated. In the case of terminating Read, input Acknowledge with “High” always, then input stop condition.

• Random read

Fig.15 RANDOM READ CYCLE TIMING

- Random Read operation allows the master to access any memory location indicated word address.
- If an Acknowledge is detected, and no STOP condition is generated by the master (µ-COM), the device will continue to transmit the data. [It can transmit all data (2kbit 256word)]
- If an Acknowledge is not detected, the device will terminate further data transmissions and await a STOP condition before returning to the standby mode.

NOTE) If an Acknowledge is detected with “Low” level, not “High” level, command will become Sequential Read. So the device transmits the next data, Read is not terminated. In the case of terminating Read, input Acknowledge with “High” always, then input stop condition.
**Sequential read**

- If an Acknowledge is detected, and no STOP condition is generated by the master (μ-COM), the device will continue to transmit the data. (It can transmit all data (2kbit 256word))
- If an Acknowledge is not detected, the device will terminate further data transmissions and await a STOP condition before returning to the standby mode.
- The Sequential Read operation can be performed with both Current Read and Random Read.

**NOTE:** If an Acknowledge is detected with “Low” level, not “High” level, command will become Sequential Read. So the device transmits the next data, Read is not terminated. In the case of terminating Read, input Acknowledge with “High” always, then input stop condition.

**Write protect**

- Using this command, writing is inhibited in lower half area. (00h to 7Fh address) If Write Protect Command is executed, cannot cancel the protection permanently. (Onetime Rom)
- This Command is cancelled, if Write Protect Command is already executed.
- During this command, please be left WP unconnected or connect WP to GND.
- This command need the period of tWR after stop condition just like Byte or Page Write command. During the tWR, next command is ignored.
Application

1) WP effective timing

WP is fixed to “H” or “L” usually. But in case of controlling WP to cancel the write command, please pay attention to [WP effective timing] as follows.

During write command input, write command is canceled by controlling WP “H” within the WP cancellation effective period.

The period from the start condition to the rising edge of the clock which take in D0 of the data (the first byte of the data for Page Write) is the cancellation invalid period. WP input is don’t care during the period. Setup time for rising edge of the SCL which takes in D0 must be more than 100ns.

The period from the rising edge of SCL which takes in D0 to the end of internal write cycle (tWR) is the cancellation effective period. In case of setting WP to “H” during tWR, WRITE operation is stopped in the middle and the data of accessing address is not guaranteed, so that write correct data again please.

It is not necessary waiting tWR (5ms max.) after stopping command by WP, because the device is stand by state.

Fig.18 WP EFFECTIVE TIMING
2) Software reset
Please execute software reset in care that the device is an unexpected state after power up and/or the command input need to be reset.
There are some kinds of software reset. Here we show three types of example as follows.
During dummy clock, please release SDA bus (tied to Vcc by pull up resistor).
During that time, the device may pull the SDA line LOW for acknowledge or outputing or read data.
If the master controls the SDA line HIGH, it will conflict with the device output LOW then it makes a current overload. It may cause instantaneous power down and may damage the device.

* COMMAND starts with start condition.
3) Acknowledge polling
Since the device ignore all input commands during the internal write cycle, no ACK will be returned.
When the master send the next command after the write command, if the device returns the ACK, it means that the
program is completed. If no ACK is returned, it means that the device is still busy.
By using Acknowledge polling, the waiting time is minimized less than $t_{WR}=5ms$.
In case of operating Write or Current Read right after Write, first, send the slave address (R/W is "HIGH" or "LOW"
respectively). After the device returns the ACK, continue word address input or data output respectively.

![Diagram of SUCCESSIVE WRITE OPERATION BY ACKNOWLEDGE POLLING](image)

4) Command cancellation by start and stop condition
During a command input, it is canceled by the successive inputs of start condition and stop condition. (Fig.21)
But during ACK or data output, the device may output the SDA line LOW. In such cases, operation of start and stop
condition is impossible, so that the reset can't work. Execute the software reset in the cases. (See Page14)
Operating the command cancel by start and stop condition during the command of Random Read or Sequential
Read or Current Read, internal address counter is not confirmed.
Therefore operation of Current Read after this is not valid. Operate a Random Read in this case.

![Diagram of COMMAND CANCELLATION BY START AND STOP CONDITION](image)
5) Notes for power supply

Vcc rises through the low voltage region in which internal circuit of IC and the controller are unstable, so that device may not work properly due to an incomplete reset of internal circuit.

To prevent this, the device has the feature of P.O.R. and LVCC.

In the case of power up, keep the following conditions to ensure functions of P.O.R. and LVCC.

(1) It is necessary to be “SDA=’H’” and “SCL=’L’ or ’H’”

(2) Follow the recommended conditions of tr, toff, Vbot for the function of P.O.R. during power up.

(3) Prevent SDA and SCL from being “Hi-Z”.

In case that condition 1. and/or 2. cannot be met, take following actions.

A) Unable to keep condition 1. (SDA is “LOW” during power up.)
→ Control SDA, SCL to be “HIGH” as figure below.

B) Unable to keep condition 2.
→ After power becomes stable, execute software reset. (See Page14)

C) Unable to keep both conditions 1 and 2.
→ Follow the instruction A first, then the instruction B.

• LVCC circuit
LVCC circuit inhibit write operation at low voltage, and prevent an inadvertent write.
Below the LVCC voltage (Typ.=1.2V), write operation is inhibited.
6) I/O circuit

- Pull up resister of SDA pin

The pull up resister is needed because SDA is NMOS open drain. Decide the value of this resister (RPU) properly, by considering VIL, IL characteristics of a controller which control the device and VOH, IOL characteristics of the device. If large RPU is chosen, clock frequency need to be slow.
In case of small RPU, the operating current increases.

- Maximum of RPU

Maximum of RPU is determined by following factor.

1. SDA rise time determined by RPU and the capacitance of bus line (CBUS) must be less than TR.
And the other timing must keep the conditions of AC spec.

2. When SDA bus is HIGH, the voltage $A$ of SDA bus determined by a total input leak (IL) of the all devices connected to the bus and RPU must be enough higher than input HIGH level of a controller and the device, including noise margin 0.2VCC.

$$V_{CC} - IL \cdot R_{PU} - 0.2V_{CC} \geq V_{IH}$$

$$R_{PU} \leq \frac{0.8V_{CC} - V_{IH}}{IL}$$

Examples : When $V_{CC}=3V$, $IL=10\mu A$, $V_{IH}=0.7V_{CC}$

According to 2)

$$R_{PU} \leq \frac{0.8 \times 3 - 0.7 \times 3}{10 \times 10^{-6}}$$

$$\leq 300 \text{ [k}\Omega\text{]}$$
• The minimum value $R_{PU}$
  The minimum value of $R_{PU}$ is determined by following factors.
  ① Meet the condition that $V_{OL\text{MAX}}=0.4V$, $I_{OL\text{MAX}}=3mA$ when the device output low on SDA line.

$$\frac{V_{CC} - V_{OL}}{R_{PU}} \leq I_{OL}$$

$\therefore \quad R_{PU} \geq \frac{V_{CC} - V_{OL}}{I_{OL}}$

② $V_{OL\text{MAX}} (=0.4V)$ must be lower than the input LOW level of the controller and the EEPROM including recommended noise margin ($0.1V_{CC}$).

$$V_{OL\text{MAX}} \leq V_{IL} - 0.1V_{CC}$$

Examples : $V_{CC}=3V$, $V_{OL}=0.4V$, $I_{OL}=3mA$, the $V_{IL}$ of the controller and the EEPROM is $V_{IL}=0.3V_{CC}$

According to ① $R_{PU} \geq \frac{3-0.4}{3\times10^{-3}}$

$\geq 867 \Omega$

and

$$V_{OL}=0.4[V]$$

$$V_{IL} = 0.3 \times 3$$

$$= 0.9[V]$$

so that condition ② is met

• Pull up resistor of SCL pin
  In the case that SCL is controlled by CMOS output, the pull up resistor of SCL is not needed.
  But in the case that there is a timing at which SCL is Hi-Z, connect SCL to $V_{CC}$ with pull up resistor.
  Several ~ several dozen $k\Omega$ is recommended as a pull up resistor, which is considered with the driving ability of the output port of the controller.

7) Connections of A0, A1, A2, WP pin
• Connections of device address pin (A0, A1, A2)
  The state of device address PIN are compared with the device address send by the master, then one of the devices which are connected to the identical bus is selected. Pull up or down these pins, or connect them to $V_{CC}$ or GND.

• Connections of WP pin
  The WP input allows or inhibits write operations. When WP is HIGH, only READ is available and WRITE to any address is inhibited. Both Read and Write are available when WP is LOW.
  In the case that the device is used as a ROM, it is recommended that WP is pulled up or connected to $V_{CC}$.
  In the case that both READ and WRITE are operated, WP pin must be pulled down or connected to GND, controlled, or be left unconnected. (WP has a pull down resister. So it is allowed to be left unconnect)
8) Notes for noise on Vcc
- About bypass capacitor

Noise and surges on power line may cause the abnormal function. It is recommended that the bypass capacitors (0.1μF) are attached on the Vcc and GND line beside the device. The attachment of bypass capacitors on the board near by connector is also recommended.

9) The notice about the connection of controller
- About Rs

The open drain interface is recommended for SDA port in I²C BUS. But, in the case that Tri-state CMOS interface is applied to SDA, insert a series resister Rs between SDA pin of the device and a pull up resister Rpu. It limits the current from PMOS of controller to NMOS of EEPROM. Rs also protects SDA pin from surges. Therefore, Rs is able to be used though SDA port is open drain.

The "H" output of controller and the "L" output of EEPROM may cause current overload to SDA line.
The maximum value of Rs
The maximum value of Rs is determined by the following factors.

1. SDA rise time determined by RPU and the capacitance of bus line (CBUS) of SDA must be less than tr. And the other timing must also keep the conditions of the AC timing.

2. When the device outputs LOW on SDA line, the voltage of the bus determined by RPU and Rs must be lower than the inputs LOW level of the controller, including recommended noise margin (0.1Vcc).

\[
\frac{(V_{CC} - V_{OL})}{R_{PU}} \times R_S + V_{OL} + 0.1V_{CC} \leq I_{OL}
\]

\[\therefore R_S \leq \frac{V_{OL} - V_{IL} - 0.1V_{CC}}{1.1V_{CC} - I_{OL}} \times R_{PU}\]

Examples: When VCC=3V, VIL=0.3VCC, VOL=0.4V, RPU=20kΩ

According to 2)

\[
R_S \leq \frac{0.3 \times 3 - 0.4 \times 3}{1.1 \times 3 - 0.3 \times 3} \times 20 \times 10^3
\]

\[\leq 1.67 \text{ [kΩ]}\]

The minimum value of Rs
The minimum value of Rs is determined by the current overload due to the conflict on the bus. The current overload may cause noises on the power line and instantaneous power down. The following conditions must be met, where I is the maximum permissible current.

The maximum permissible current depends on Vcc line impedance and so on. It needs to be less than 10mA for EEPROM.

\[
\frac{V_{CC}}{R_S} \leq I
\]

\[\therefore R_S \geq \frac{V_{CC}}{I}\]

Examples: When VCC=3V, I=10mA

\[
R_S \geq \frac{3}{10 \times 10^3}
\]

\[\geq 300 \text{ [Ω]}\]
10) The special character data
The following characteristic data are typ value.

Fig.22 High input voltage \( V_{IH} \)
(A0,A1,A2,SCL,SDA,WP)

Fig.23 Low input voltage \( V_{IL} \)
(A0,A1,A2,SCL,SDA,WP)

Fig.24 Low output voltage \( V_{OL} \)
\( -I_{OL} \)
\( (V_{CC}=1.8V) \)

Fig.25 Low output voltage \( V_{OL} \)
\( -I_{OL} \)
\( (V_{CC}=2.5V) \)

Fig.26 Input leakage current \( I_{IL} \)
\( (A0,A1,A2,SCL,WP) \)

Fig.27 Input leakage current \( I_{IL} \)
\( (WP) \)

Fig.28 Output leakage current \( I_{OL} \)
\( (SDA) \)

Fig.29 Write operating current \( I_{CC1} \)
\( (f_{SCL}=400kHz) \)

Fig.30 Read operating current \( I_{CC2} \)
\( (f_{SCL}=400kHz) \)
Memory ICs

Fig. 40 Input data hold time \( t_{HD:DAT}(LOW) \)

Fig. 41 Input data setup time \( t_{SU:DAT}(HIGH) \)

Fig. 42 Input data setup time \( t_{SU:DAT}(LOW) \)

Fig. 43 Output data delay time \( t_{PD0} \)

Fig. 44 Output data delay time \( t_{PD1} \)

Fig. 45 Output data hold time \( t_{DH0} \)

Fig. 46 Output data hold time \( t_{DH1} \)

Fig. 47 Stop condition setup time \( t_{SU:STO} \)

Fig. 48 BUS free time \( t_{BUF} \)
Memory ICs

Fig.49 Write cycle time \( t_{\text{wr}} \)

Fig.50 Noise spike width \( t_{\text{I(SCL H)}} \)

Fig.51 Noise spike width \( t_{\text{I(SCL L)}} \)

Fig.52 Noise spike width \( t_{\text{I(SDA H)}} \)

Fig.53 Noise spike width \( t_{\text{I(SDA L)}} \)

Fig.54 WP setup time \( t_{\text{SU:WP}} \)

Fig.55 WP high period \( t_{\text{HIGH:WP}} \)
Appendix

Notes

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